

# INSTRUCTIONS

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T 3 3 0 - L G S H L

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L A R G E S P E C I M E N  
H O L D E R

**JEOL**

No. ISMT330LGSHL-1

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*Bei Warning*

*Load Current*

*Kontrollleuchte  
abgeblenkt!*

 JEOL LTD. / JEOL TECHNICS LTD.

Tokyo Japan

## 1 GENERAL

This holders are used to observe a specimen of 2"/3" dia. size .  
Also can be observe 10mm dia.×10mmh ×20 pcs.  
Specimen exchange is specimen stage draw-out type.

## 2 SPECIFICATIONS

- Specimen size: 10mm dia.×10mmh ×20 pcs.  
2"(51mm) dia.×10mmh  
3"(76mm) dia.×10mmh
- Specimen movement range :(LGS) X=40mm,Y=80mm,  
T= -10~90°  
R=360 ° endless
- Working distance(WD): 10~48 mm
- Observable area: Whole area of specimen.(MAX.)
- Specimen exchange: Specimen stage draw-out type.  
(Can not be used airlock chamber.)

## 3 COMPOSITIONS

- Large specimen holder(51mm dia.) . . . . . 1
- Large specimen holder(76mm dia.) . . . . . 1
- Specimen stub(51mm dia. ×5mmh,10mmh) . . . . . 1 each
- Specimen stub(76mm dia. ×5mmh,10mmh) . . . . . 1 each
- Adapter (for 10mm dia.×10mmh ×20 pcs.) . . . . . 1
- Specimen stubs(10mm dia.×10mmh ) . . . . . 20

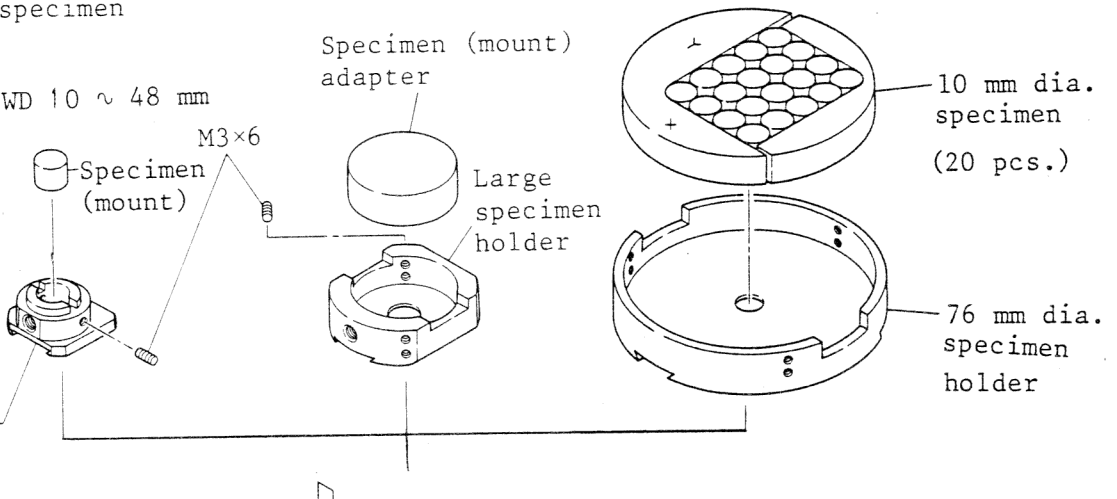
## 4 MOUNT&REMOVE

1. Draw out the specimen stage.
2. Mount or remove specimen (adapter/stub).Refer to T330 INSTRUCTIONS.  
For 10mm dia.×10mmh ×20 pcs., use the 76 mm dia. specimen holder and its adapter.

10 mm dia.  
specimen

32 mm ~ 76 mm dia.

WD 10 ~ 48 mm



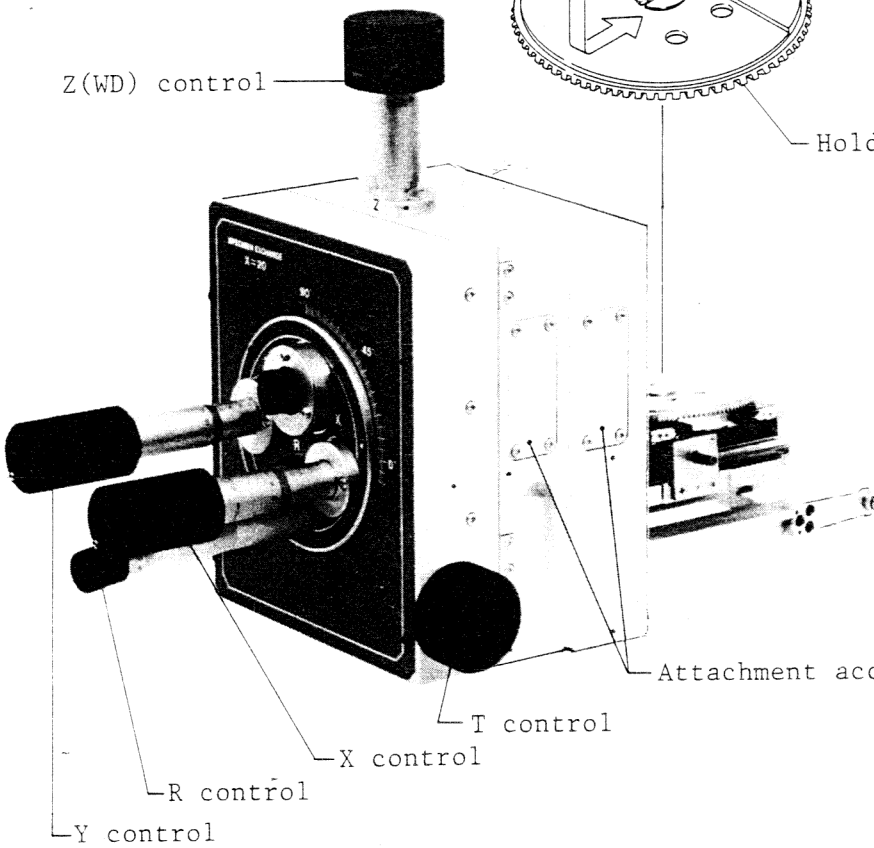
10 mm dia.  
specimen  
holder

10 mm dia.  
specimen  
(20 pcs.)

76 mm dia.  
specimen  
holder

Z(WD) control

Holder receiver



Attachment access ports

Specimen mounting

## 5 SPECIMEN MOVEMENT RANGES

• SEI(secondary electron image observation)

BEIS is retracted and no other attachments are installed on specimen chamber.

R=360 ° endless

WD mm	10~14		15~19		20~24		25~29		30~34	
Y(mm)	0~80		0~10	10~80	0~10	10~80	0~10	10~80	0~10	10~80
T(°)	0~20		0~25	0~30	0~25	0~35	0~25	0~40	-10~25	-10~45
X(mm)										
0										
10										
20										
30										
40										

WD mm	35~39			40~47			48						
Y(mm)	0~10			10~80			0~10			10~80			
T(°)	-10~25			-10~50	50~60	-10~25	-10~55	55~90	-10~25			-10~60	60~90
X(mm)													
0													
10													
20													
30													
40													

• Using BEIS(Backscatterd electron image observation)

BEIS is inserted and no other attachments are installed on specimen chamber.

R=360 ° endless

WD mm	10~48
Y(mm)	0~80
T(°)	0
X(mm)	
0	
10	
20	
30	
40	